

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MARUYAMA ET AL.	
		Examiner Jared W. Radkiewicz	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,488,719	01-1996	Kaplan et al.	707/100
*	B	US-6,269,260	07-2001	Shin et al.	455/550.1
	C	US-			
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	K	US-			
	L	US-			
''	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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